MSE-628

CCMX Advanced Course - Advanced X-ray Diffraction Methods for Coatings: strain, defects and deformation analysis of thin films

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Cursus	Sem.	Type
Materials Science and Engineering		Opt.

Language of teaching	English
Credits	1
Session	
Exam	Written
Workload	30h
Hours	**25**
Courses	15
TP	10
Number of positions	**16**

Frequency

Every 2 years

Remark

Next time: Autumn 2027

Summary

After introducing thin film and HR-XRD characterisation methods, theory and limitations are discussed, including examples and how the film structure influences its characteristics. Protocols are presented for establishing reproducible and reliable measurements, and for interpreting their results.

Content

Assessment methods

Written exam